

Notice of References Cited	Application/Control No. 10/559,698		Applicant(s)/Patent Under Reexamination CLAUSEN ET AL.	
	Examiner CHUONG T. HO		Art Unit 2476	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-2009/0257526	10-2009	Wang et al.	375/298
*	C	US-2005/0069045	03-2005	Laaser, Peter	375/260
*	D	US-2004/0234006	11-2004	Leung, Stephen Y	375/316
*	E	US-7,397,860	07-2008	Duvaut et al.	375/260
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*	H	US-6,314,146	11-2001	Tellado et al.	375/346
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
	U	Henkel et al. (PAR reduction revisited: an extension to Tellado's method; 6th, International OFDM Workshop; 2001; Pages 31-1 - to 31-6) International OFDM Workshop Year 2001			
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.